

Historical Data Since **Since 1947** IEEE International Frequency Control Symposium (**IFCS**) Conferences

and

Time Curves of the 2008 IEEE IUS for Future Conference Planning

Note: A Microsoft Excel version of these plots for details of the data is accessible at: https://ewh.ieee.org/conf/ius_2008/z_doc_misc/0_oper_ius2008_plots_ifcs.xls

Notes

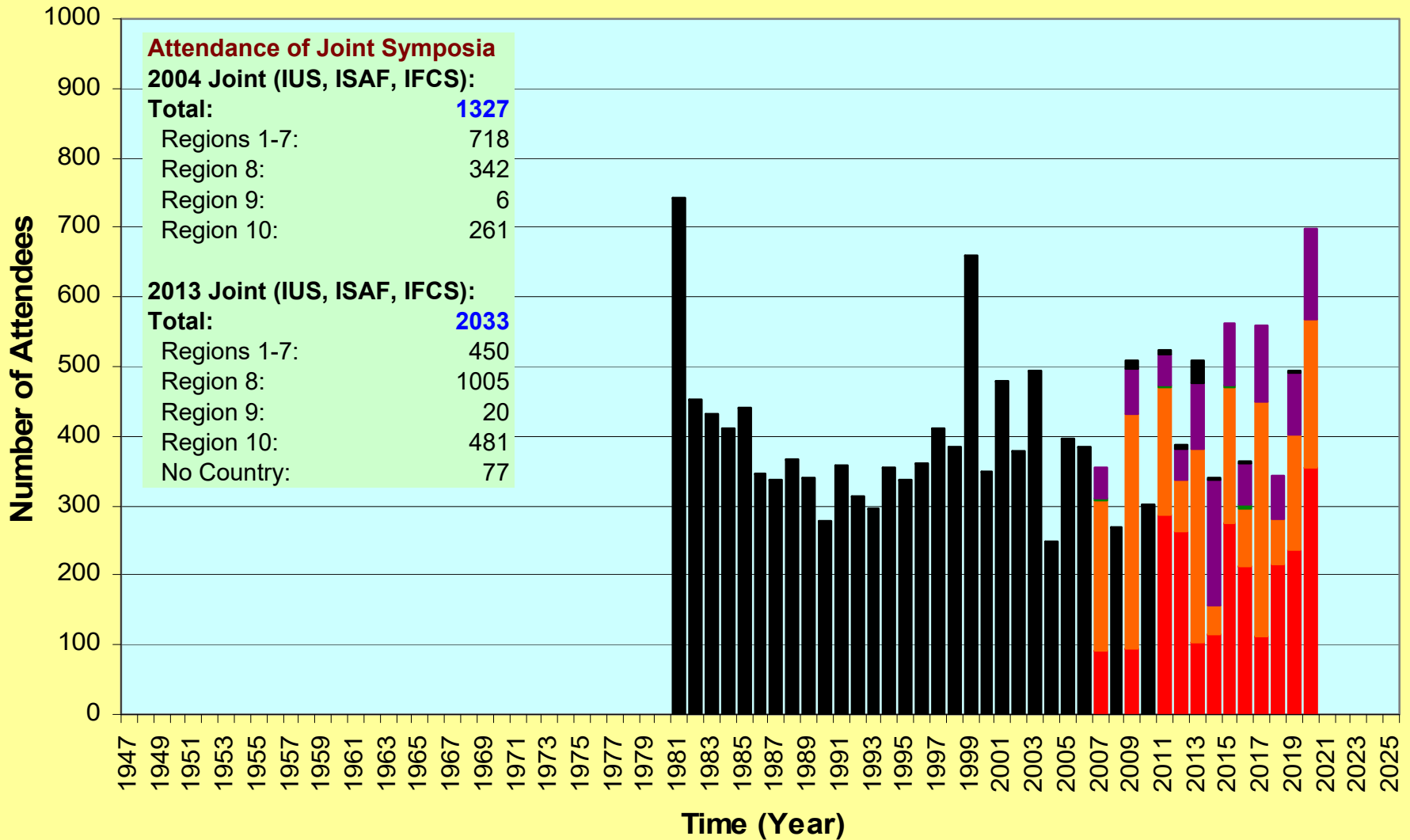
These charts are based on data in the spreadsheet: “[0_oper_ius2008_plots_ifcs.xls](#)”. Comments in the .xls spreadsheet indicate where the data were obtained. The data were collected from various reports and from some individuals. However, they are far from perfect. There are many missing data. There may be inconsistencies such as the number of abstracts accepted is more than submitted or less than the number of conference proceedings papers published in some years. These data are what I have so far and many of the original data might have already been permanently lost.

This underscores the importance that, to collect conference historical data, each conference should fill out the standard data collection form “[00_uffcs_conf_data_collection_fillable.pdf](#)” soon after the conference while the memory of the conference is still fresh.

Currently, among the three annual UFFC-S conferences, historical data of IEEE IUS are relatively complete and consistent. Thank you all for those who made reports or who provided the data.

of Attendees of the IEEE International Frequency Control Symposia (IFCS) by IEEE Regions (Since 1947) - "0" values mean that data are not available for those years

■ IEEE R1-7 (US/Canada)
 ■ IEEE R8 (Europe/MiddleEast/Africa)
 ■ IEEE R9 (LatinAmerica)
 ■ IEEE R10 (Asia/Pacific)
 ■ No Country

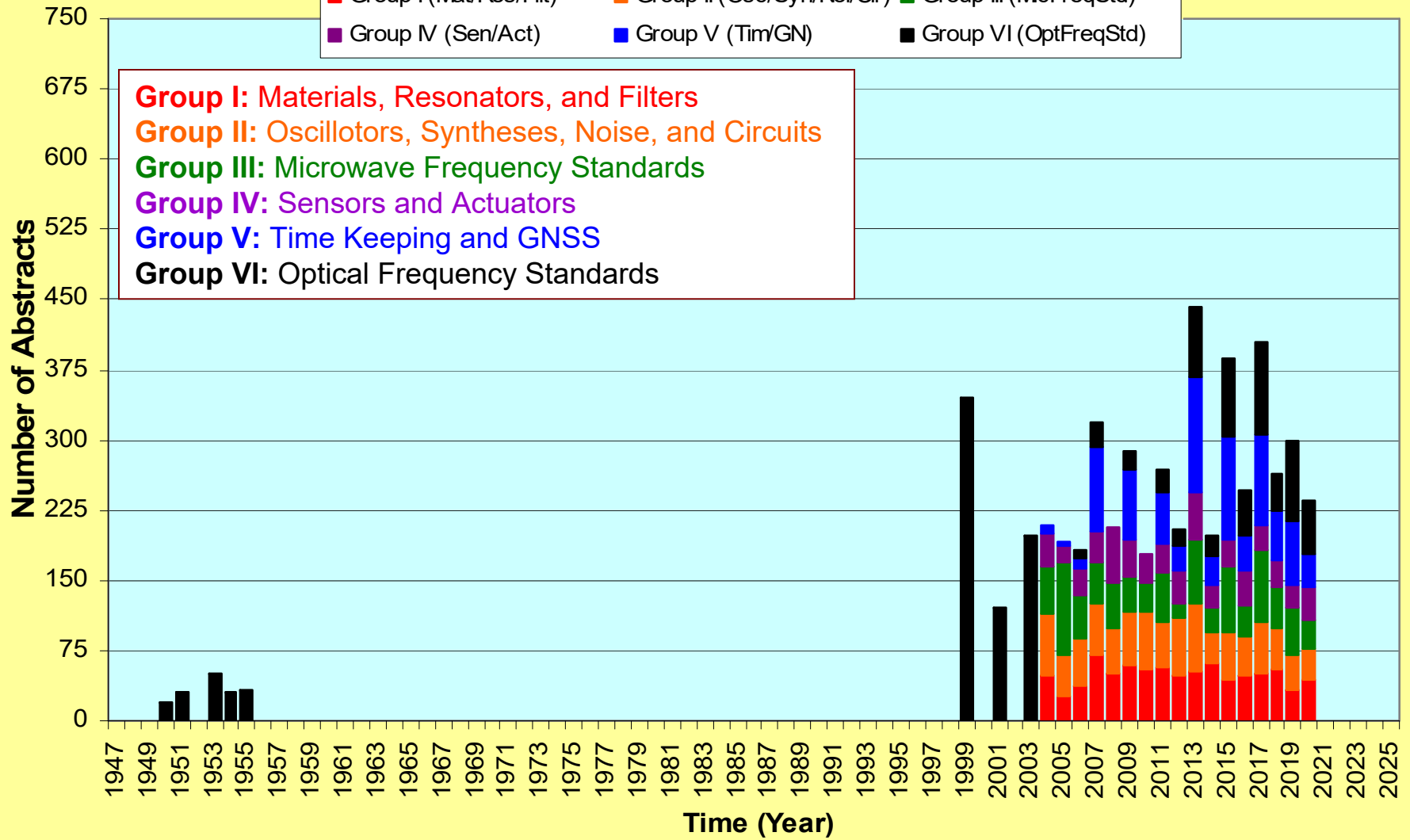


of Abstracts Submitted to the IEEE International Frequency Control Symposia (IFCS) by Each Group (Since 1947)

- "0" values mean that data are not available for those years; "Solid Bar" means no Group data

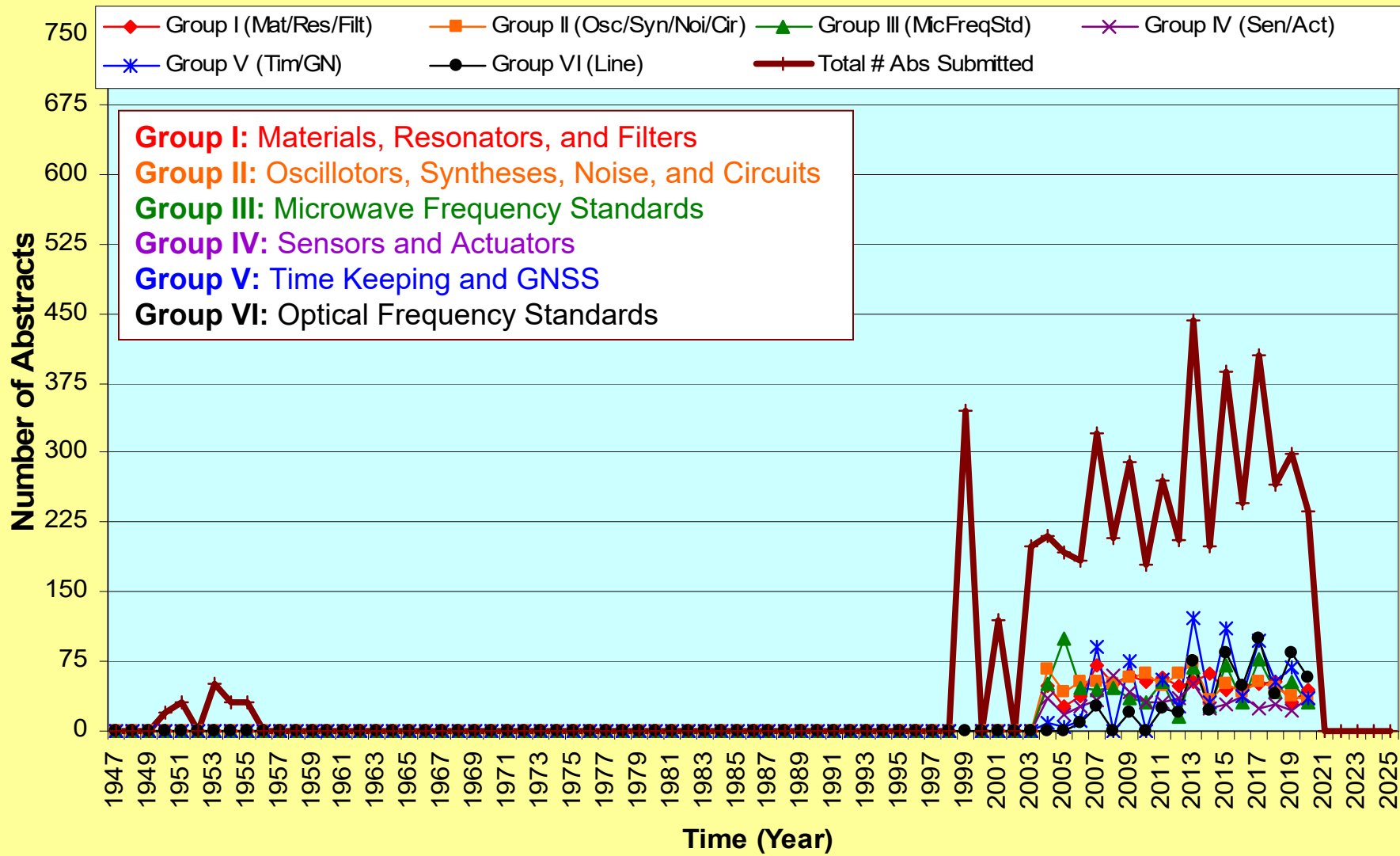
■ Group I (Mat/Res/Filt)	■ Group II (Osc/Syn/Noi/Cir)	■ Group III (MicFreqStd)
■ Group IV (Sen/Act)	■ Group V (Tim/GN)	■ Group VI (OptFreqStd)

Group I: Materials, Resonators, and Filters
Group II: Oscillators, Syntheses, Noise, and Circuits
Group III: Microwave Frequency Standards
Group IV: Sensors and Actuators
Group V: Time Keeping and GNSS
Group VI: Optical Frequency Standards



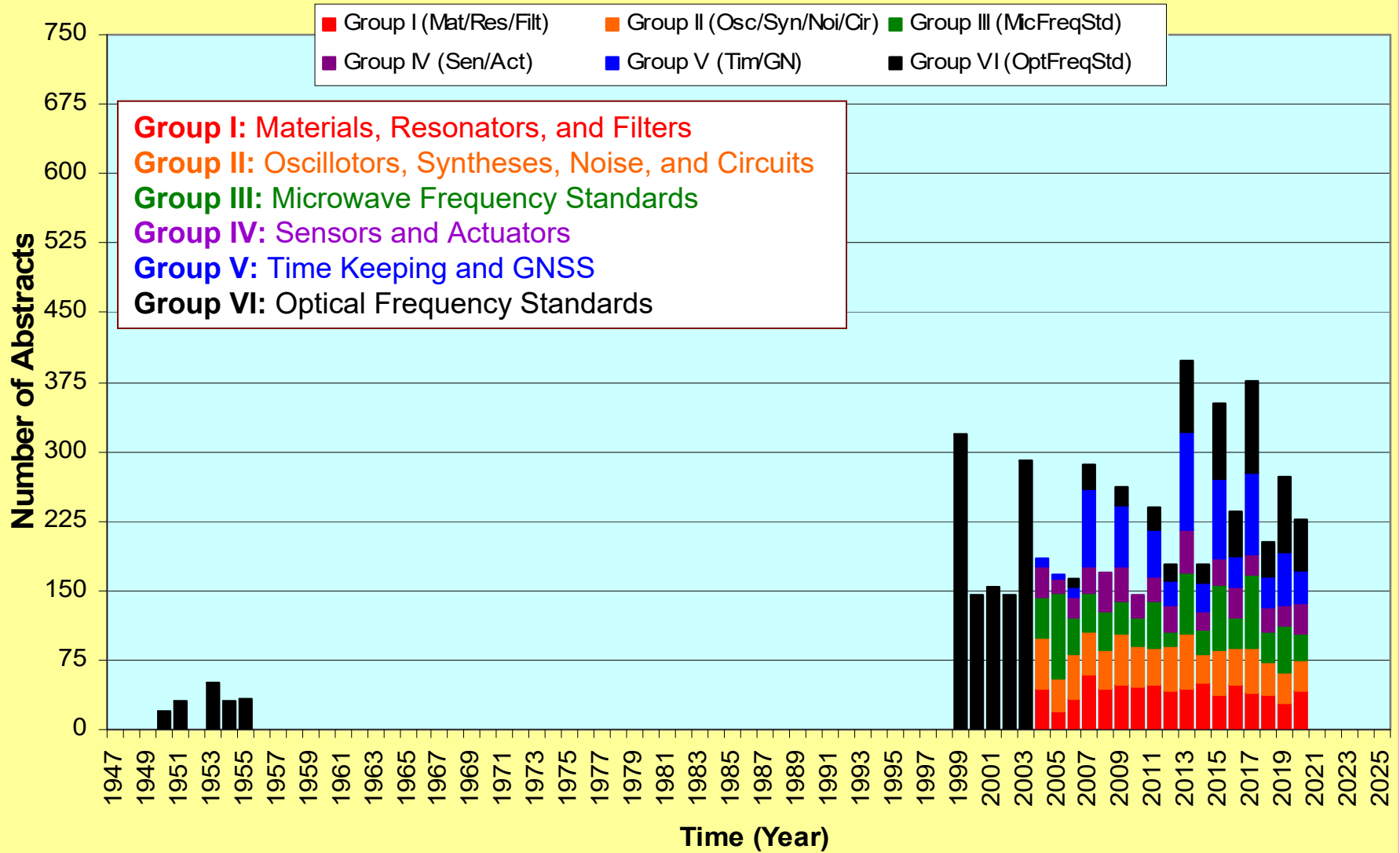
of Abstracts Submitted to the IEEE International Frequency Control Symposia (IFCS) by Each Group (Since 1947)

- "0" values mean that data are not available for those years



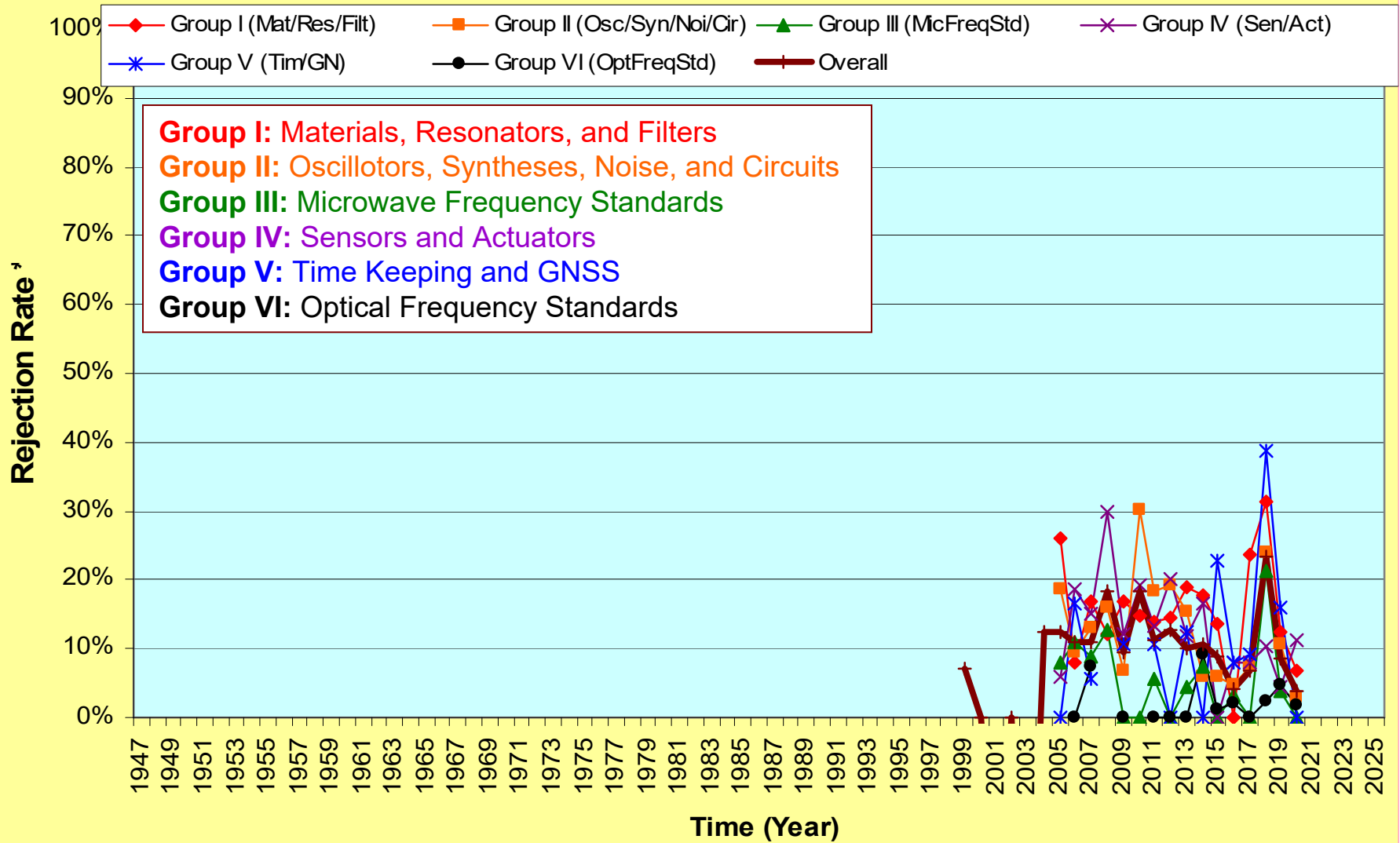
of Abstracts Accepted for the IEEE International Frequency Control Symposia (IFCS) by Each Group (Since 1947)

- "0" values mean that data are not available for those years; "Solid Bar" means no Group data



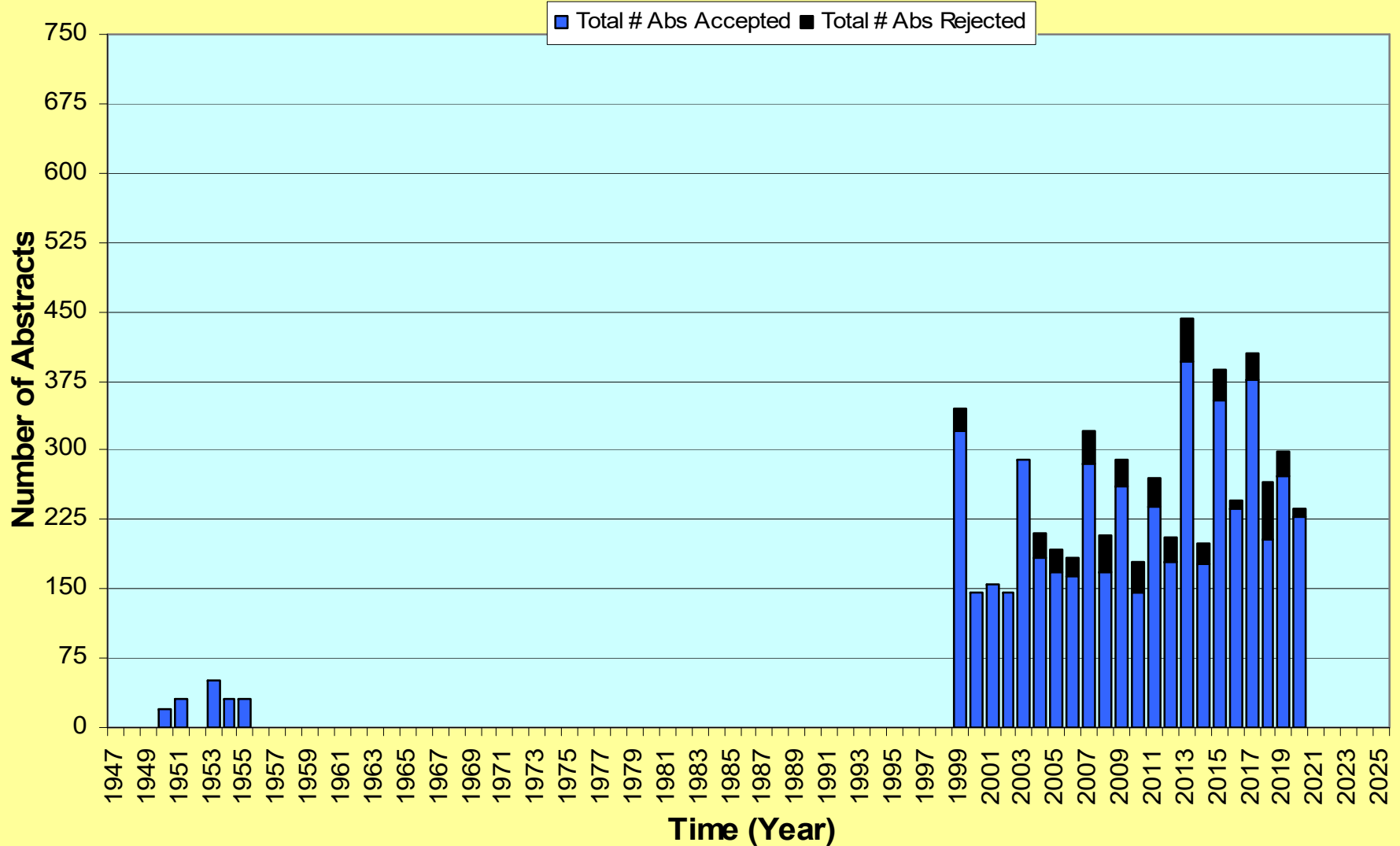
Rejection Rate (%) of the IEEE International Frequency Control Symposia (IFCS) by Each Group (Since 1947)

- "0" values mean that data are not available for those years



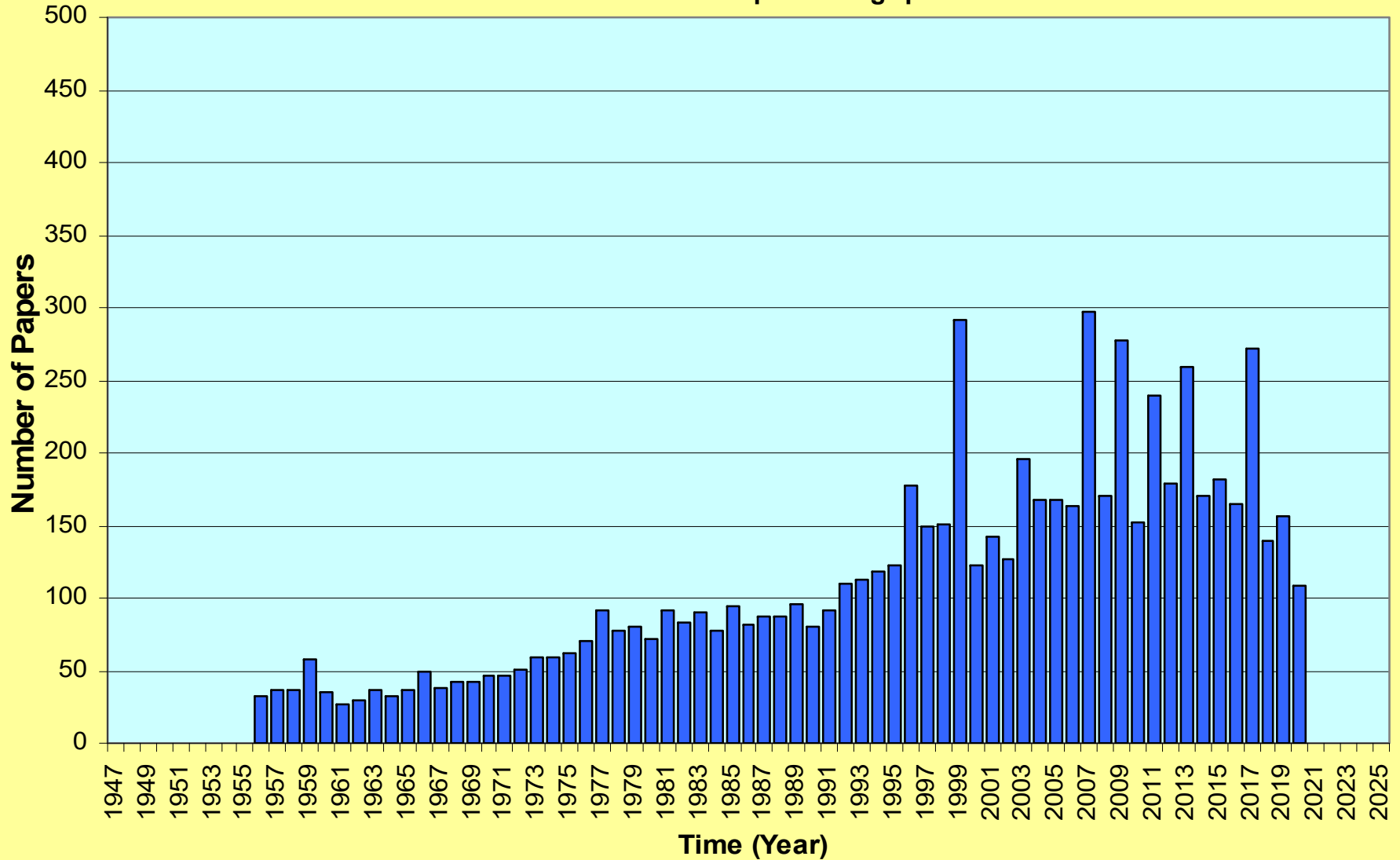
of Abstracts Accepted vs Rejected by the IEEE International Frequency Control Symposia (IFCS) (Since 1947)

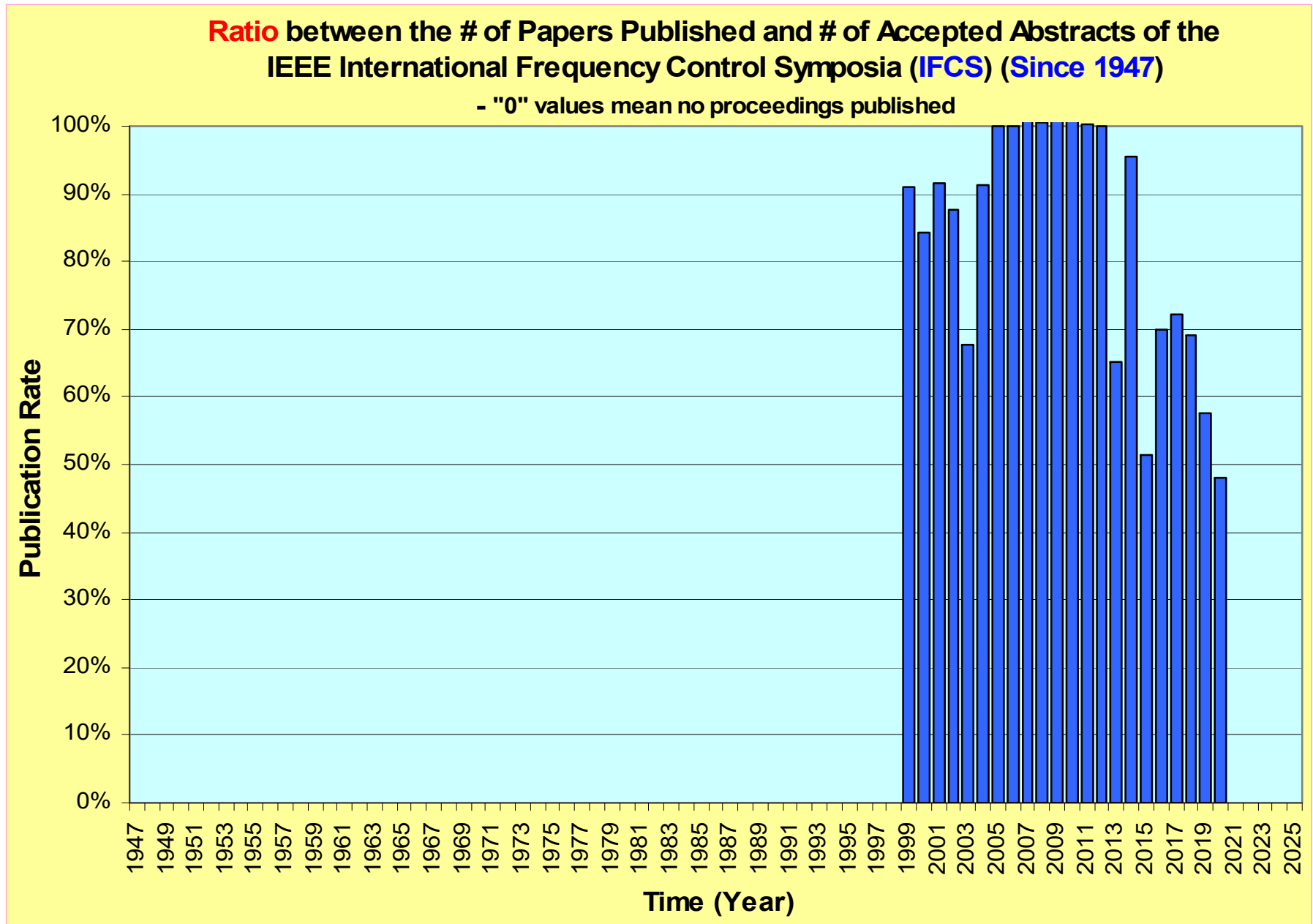
- "0" means that the rejection data are not available for those years



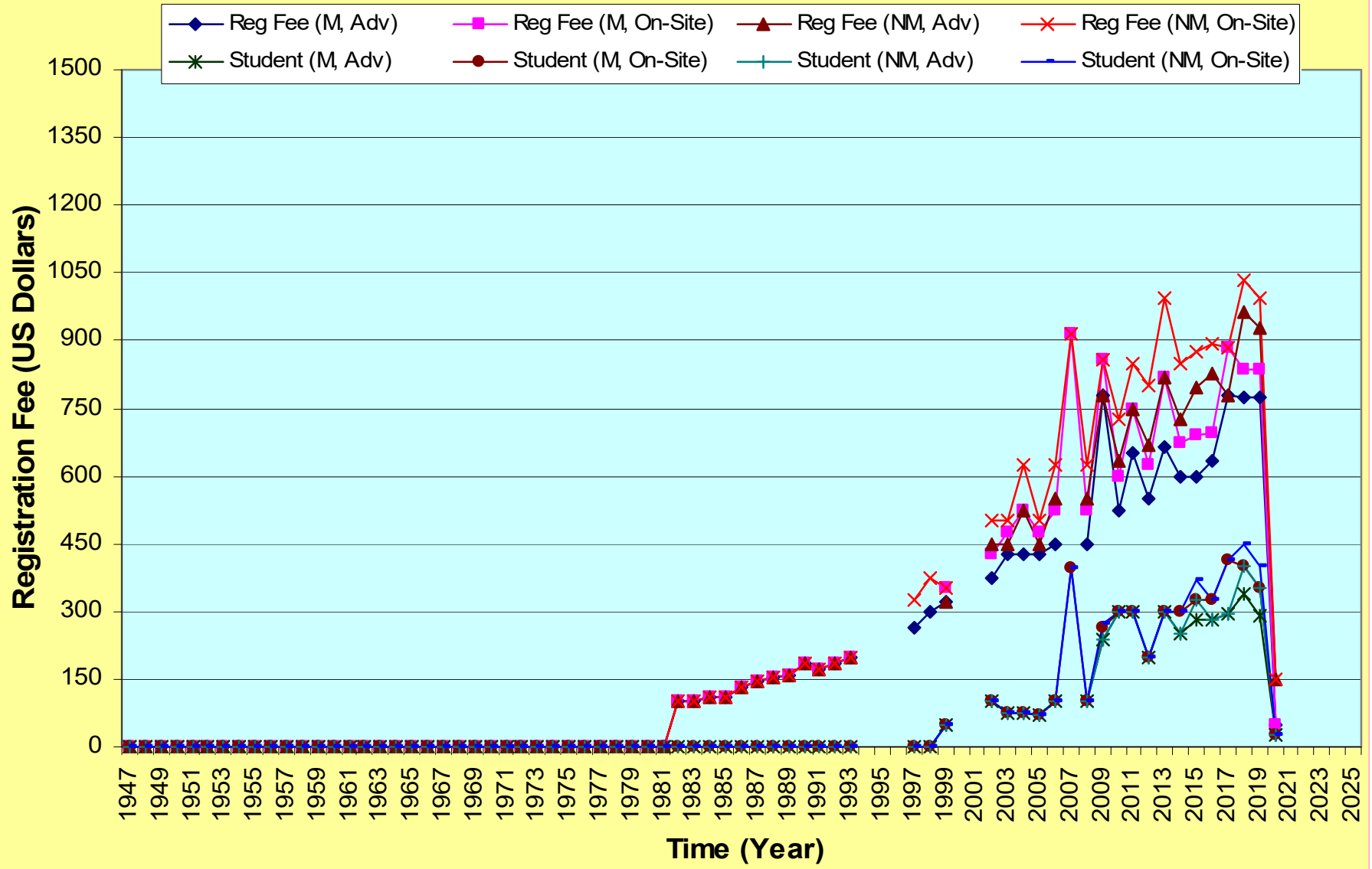
of Papers Published in the Proceedings of the IEEE International Frequency Control Symposia (IFCS) (Since 1947)

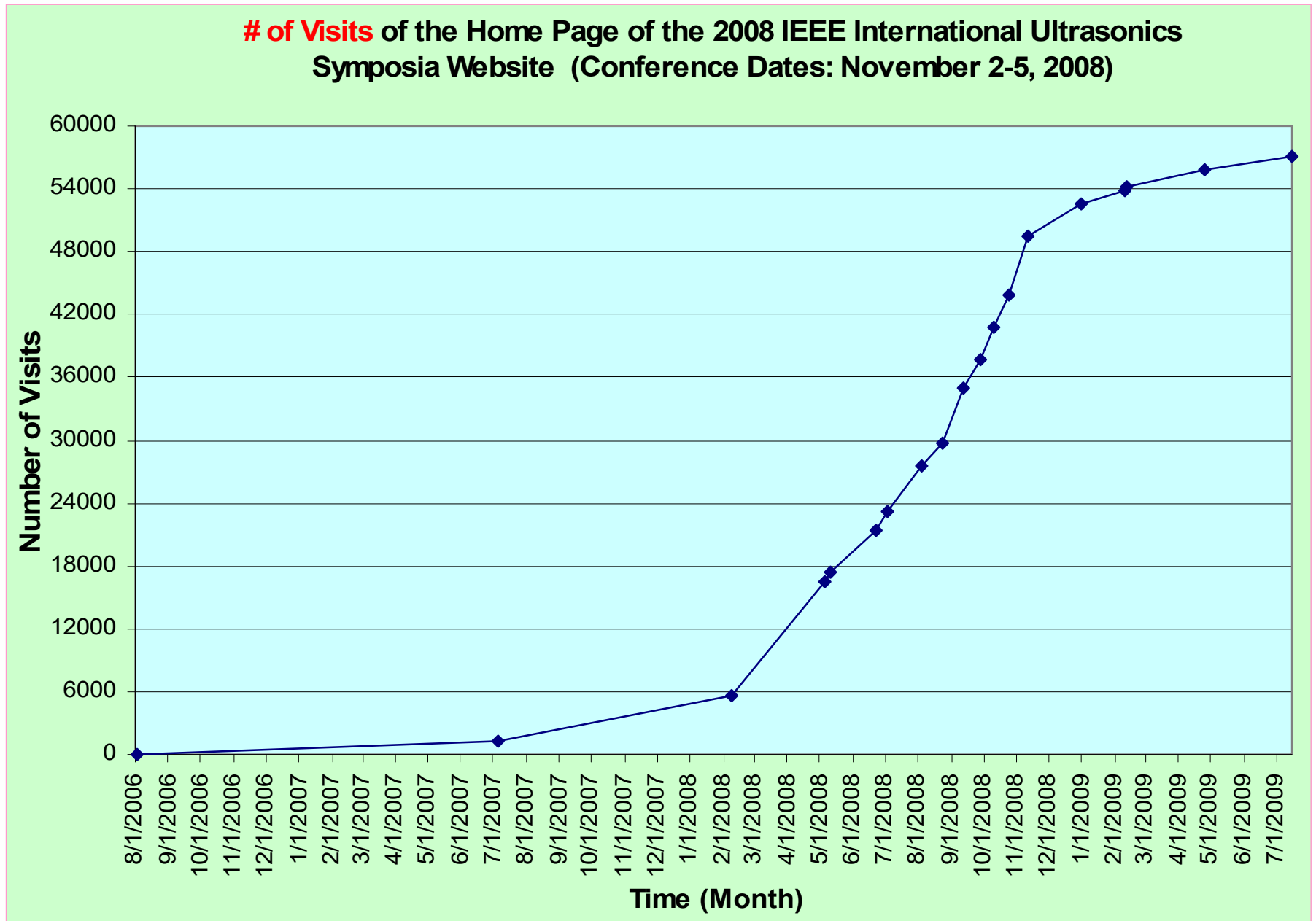
- "0" values mean no proceedings published



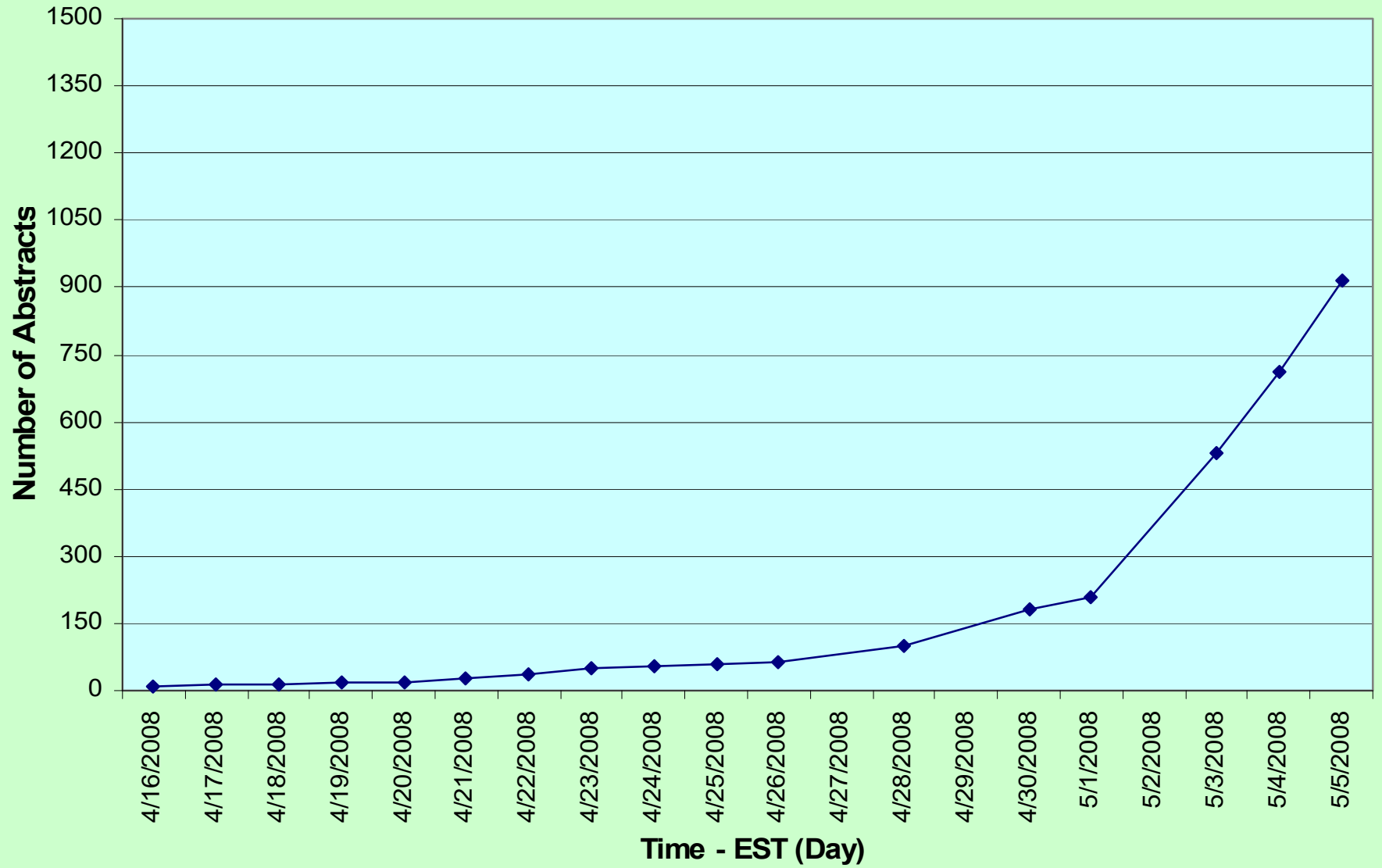


Registration Fees of the IEEE International Frequency Control Symposia (IFCS) (Since 1947) - "0" values mean that data are not available for those years

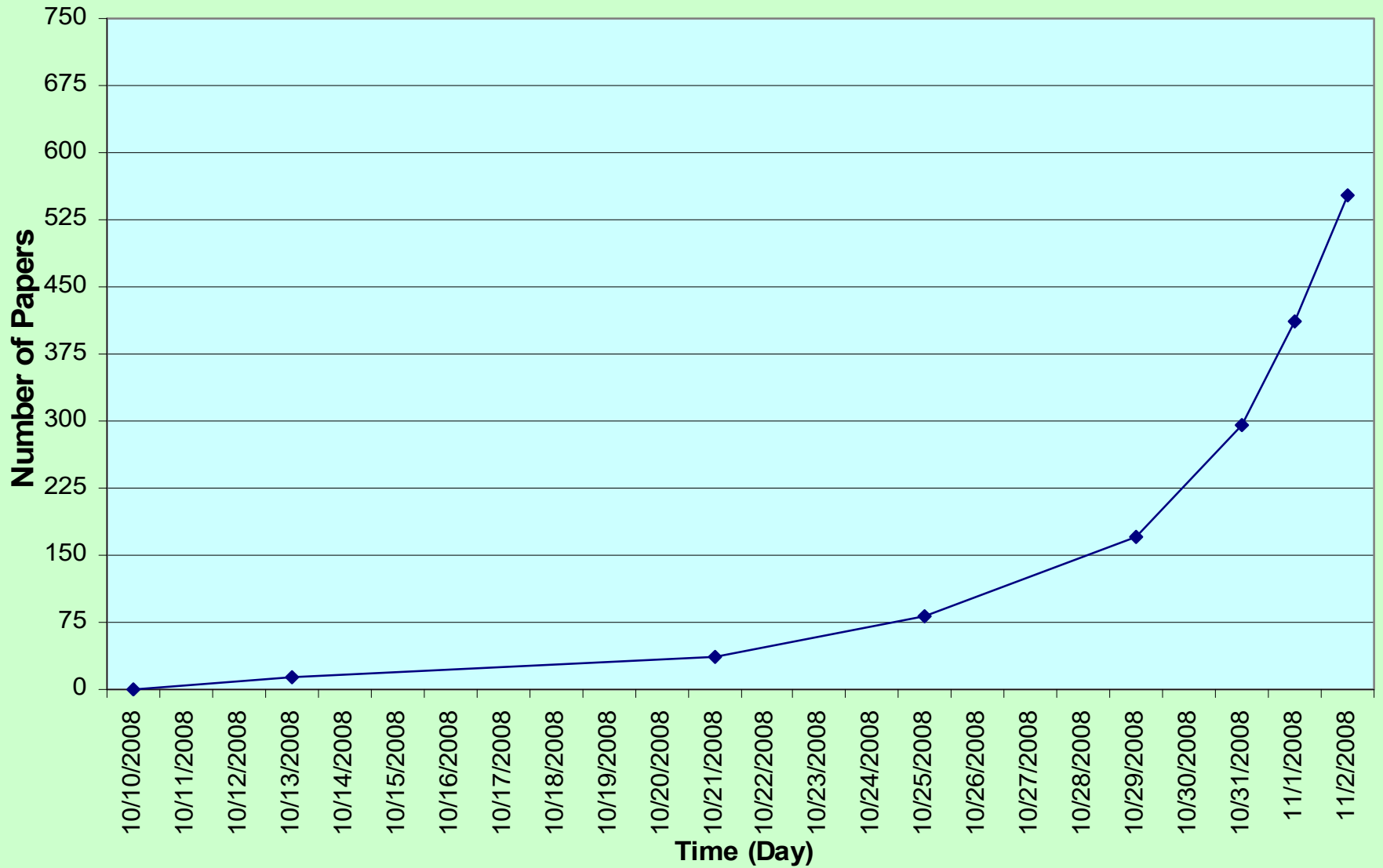




of Abstracts Successfully Submitted to the 2008 IEEE International Ultrasonics Symposium (Submission Deadline: May 4, 2008, PST / May 5, EST)



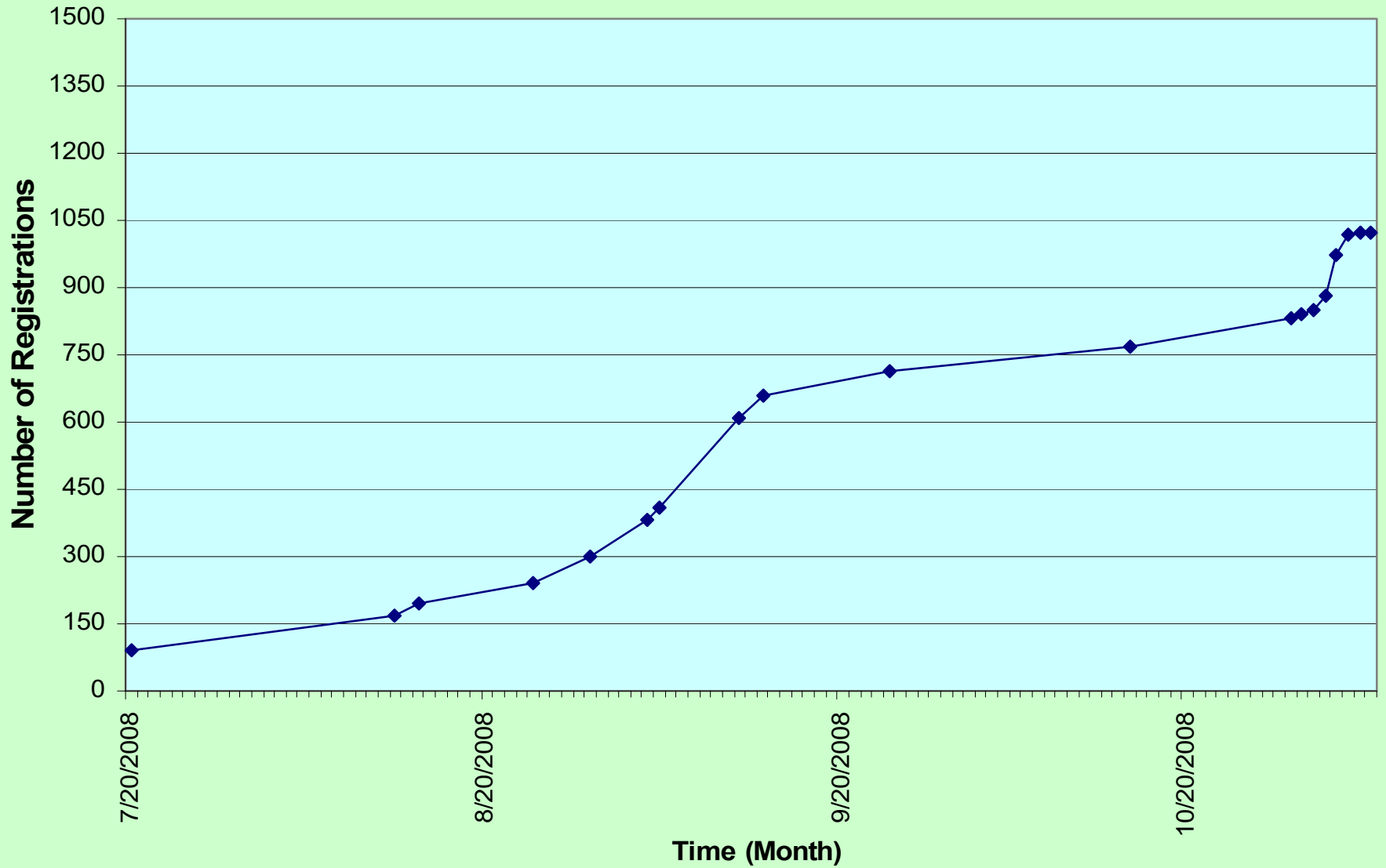
of Papers Submitted Successfully to the 2008 IEEE International Ultrasonics Symposium (Submission Deadline: Nov. 2, 2008, Beijing Time)



**# of Short Course Registrations of the 2008 IEEE International Ultrasonics Symposium (Early Registration Opened on July 20, 2008)
(Conference Dates: November 2-5, 2008)**



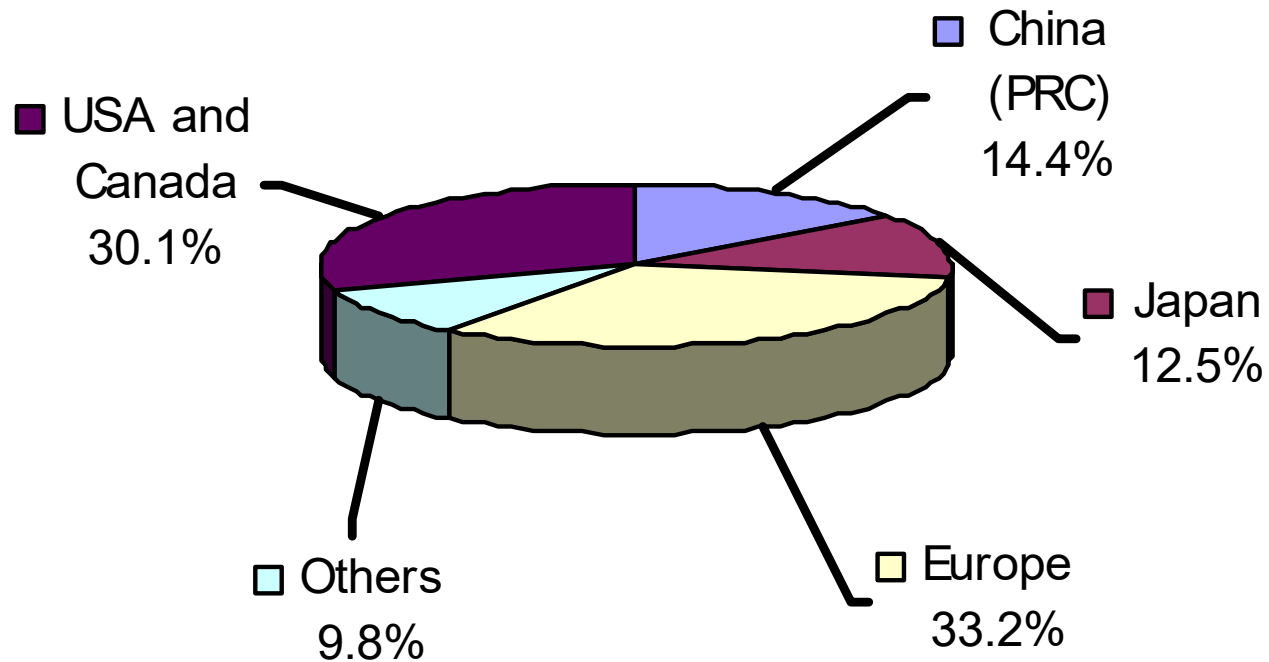
of Conference Registrations of the 2008 IEEE International Ultrasonics Symposium (Conference Dates: November 2-5, 2008)



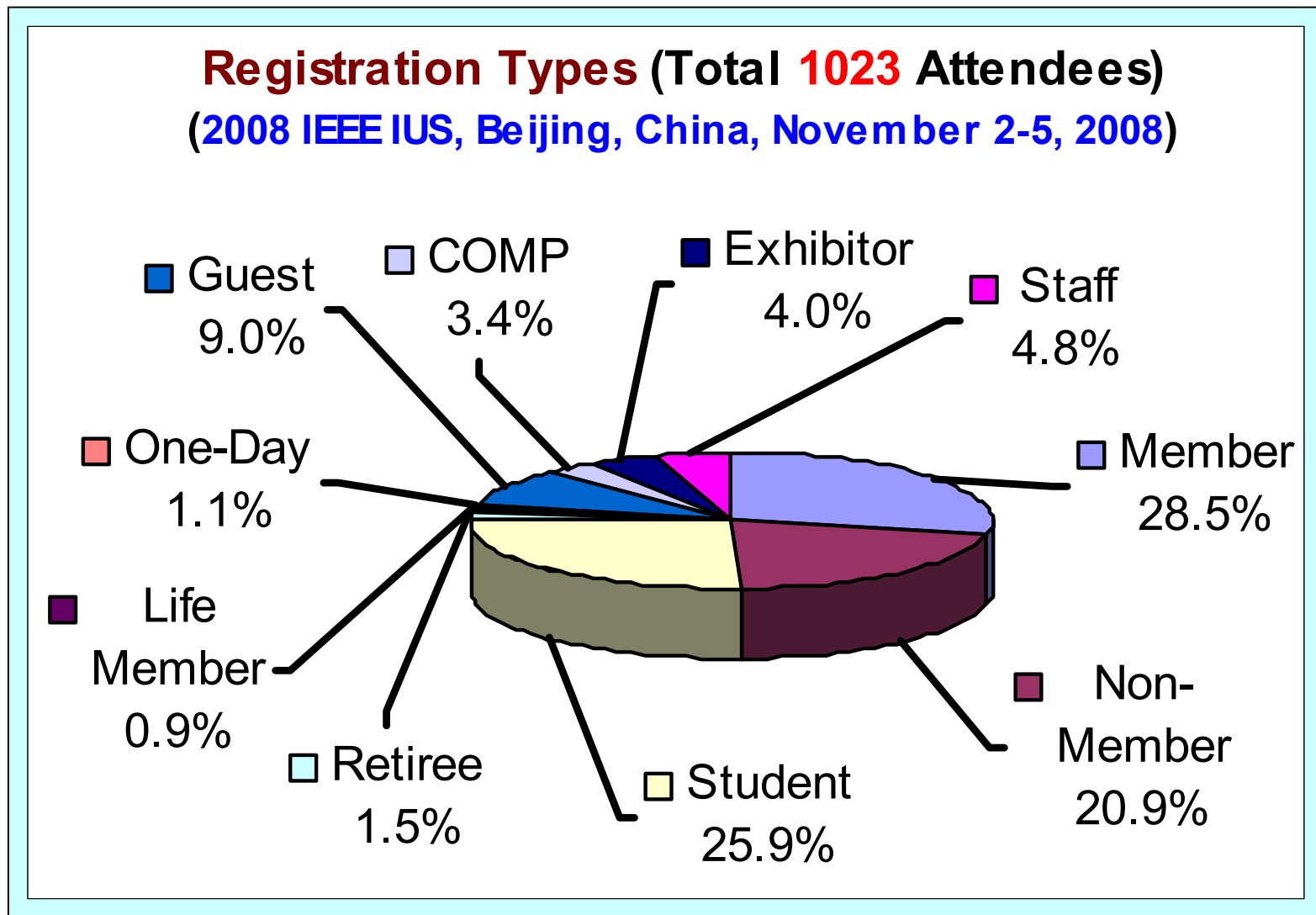
1. Abstracts (674) accepted from 37 countries

Accepted Abstract by Country in the Technical Program (Total 674)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



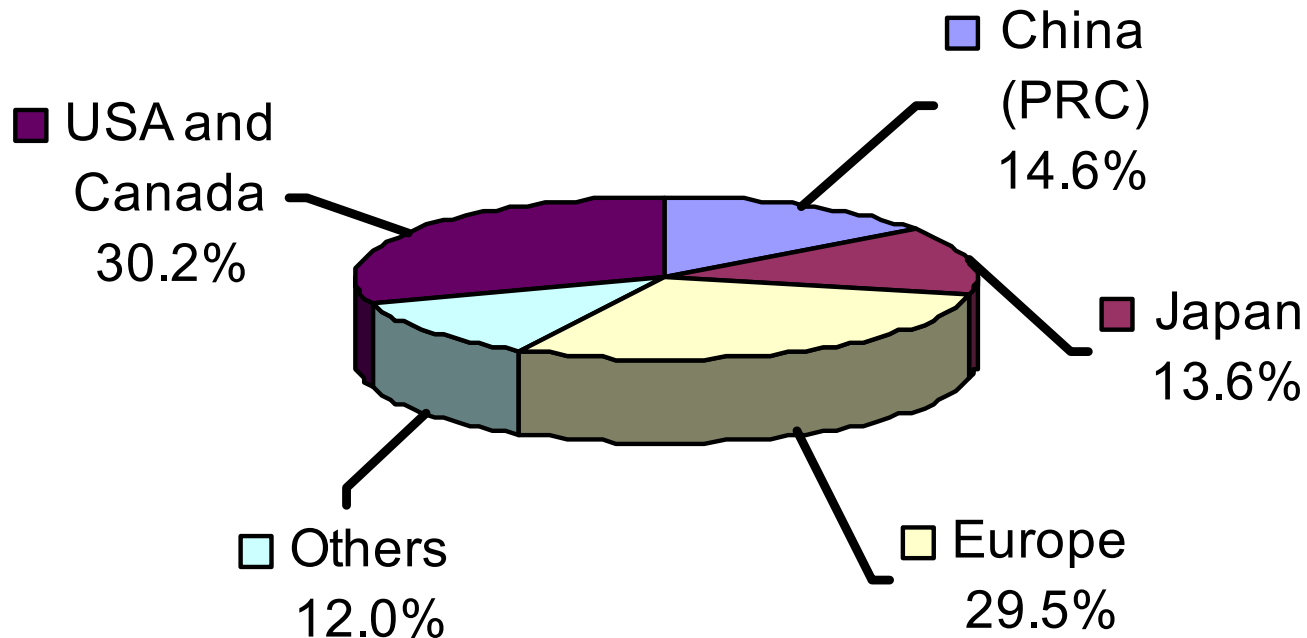
2. Attendees (1023) in 10 categories



Note: Most “COMP” registrants are invited speakers

3. Conference Registration from 32 countries

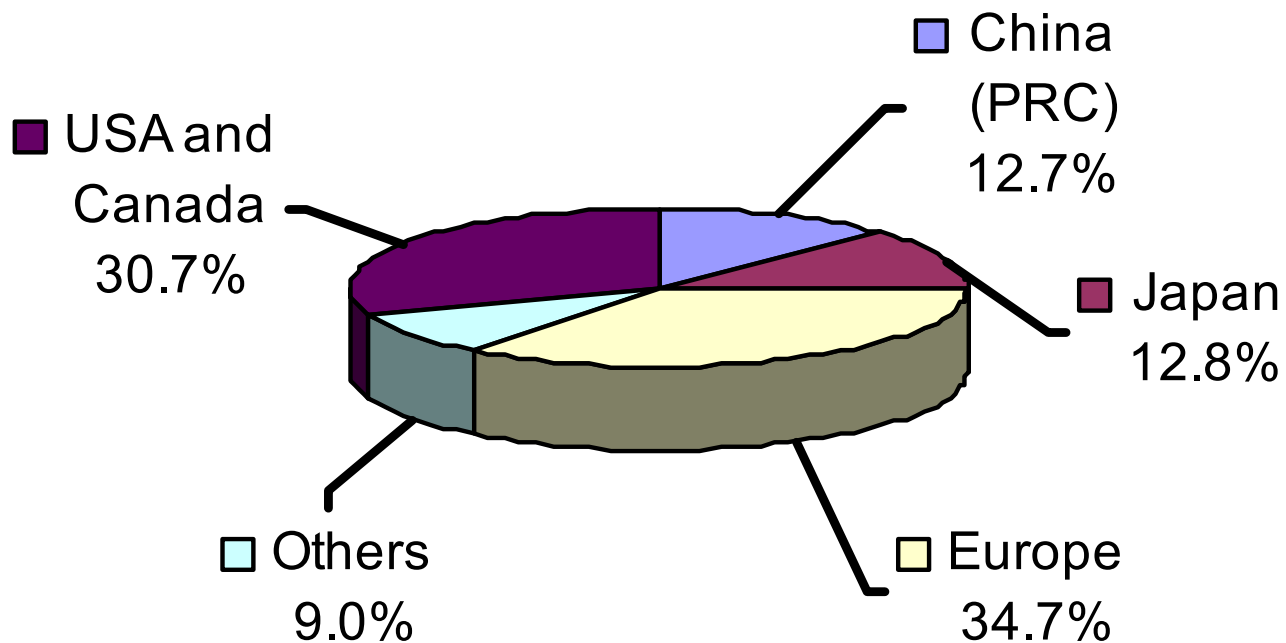
Registration Distribution by Country (Excluding Staff and Exhibitors)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



Note: The country counts of all charts do not include those of coauthors

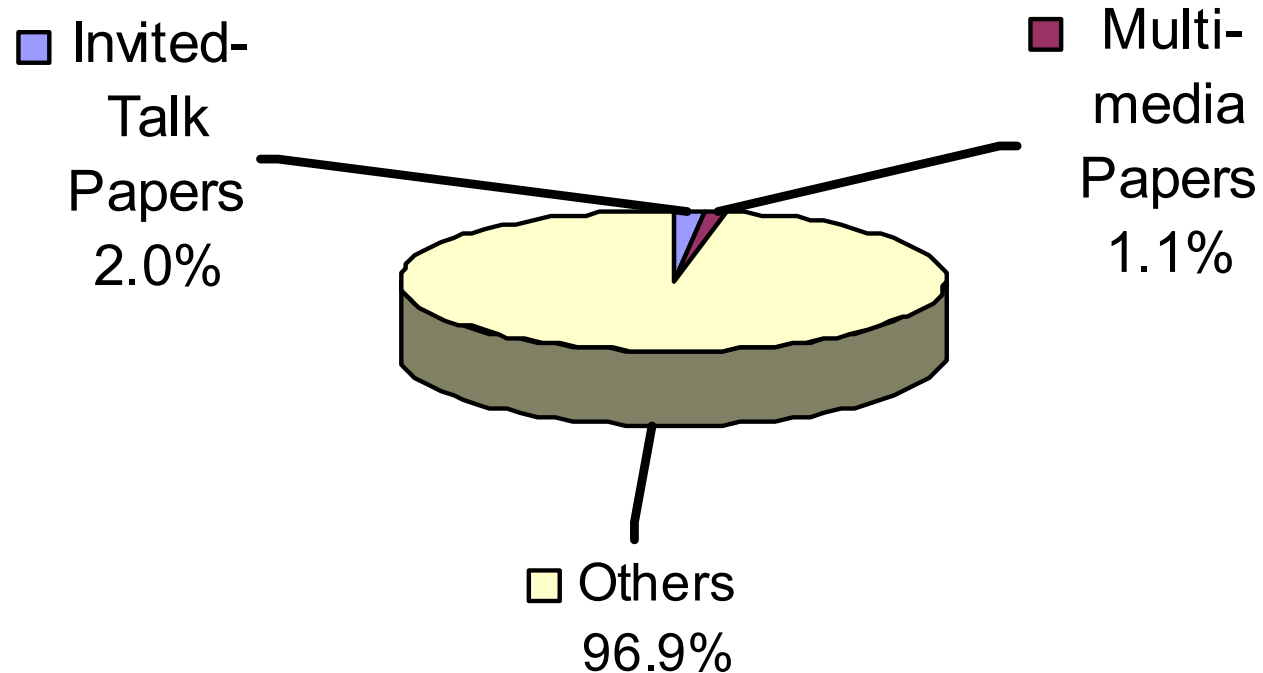
4. Papers (553) published from 32 countries

Number of Papers in Proceedings by Country
(Total 553 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



5. Papers (553) published in 3 categories

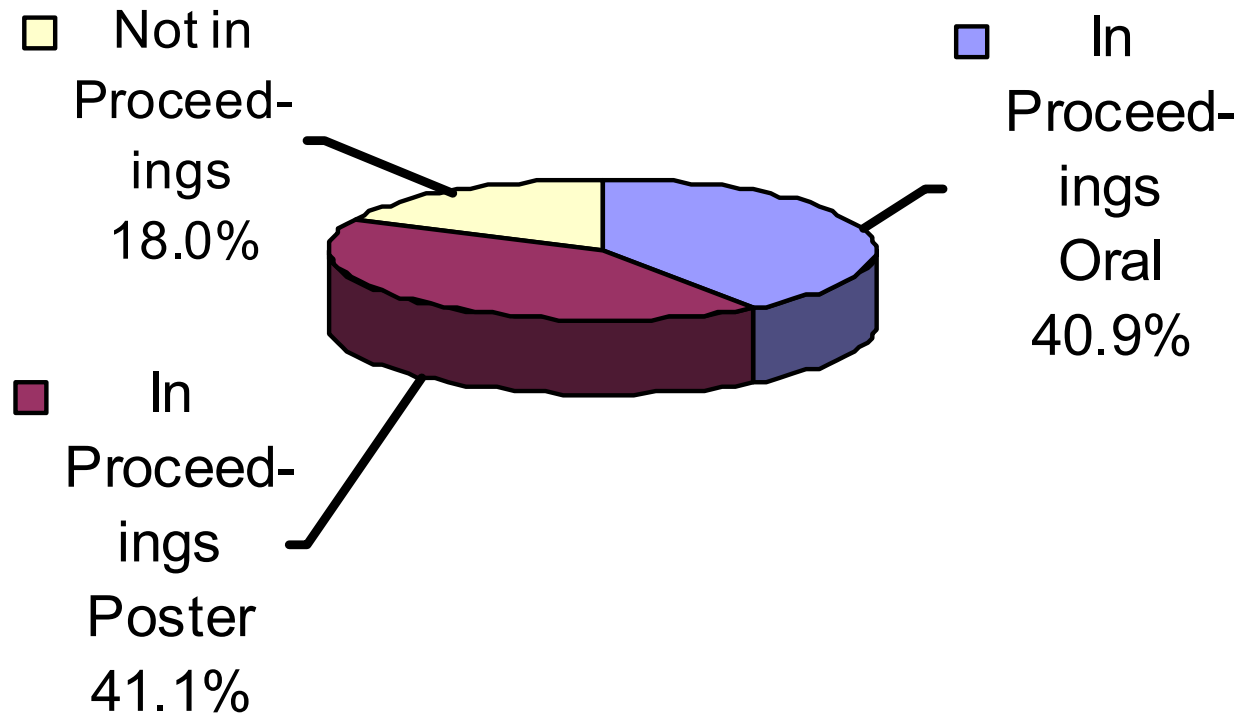
Paper Types in Proceedings (Total 553 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



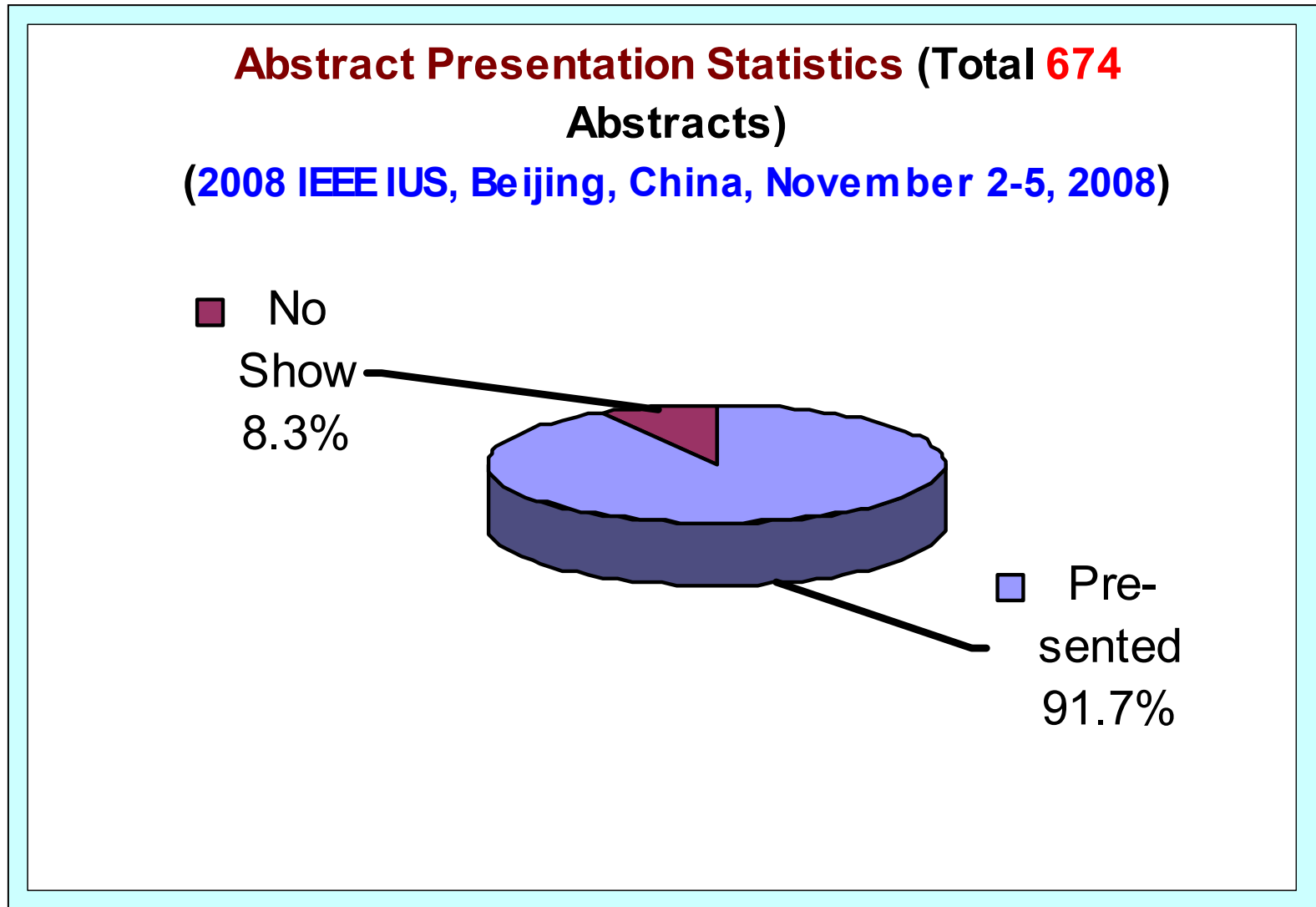
6. Papers (553) published from accepted abstracts (674)

Abstracts Statistics for Proceedings (Total 674 Abstracts)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)

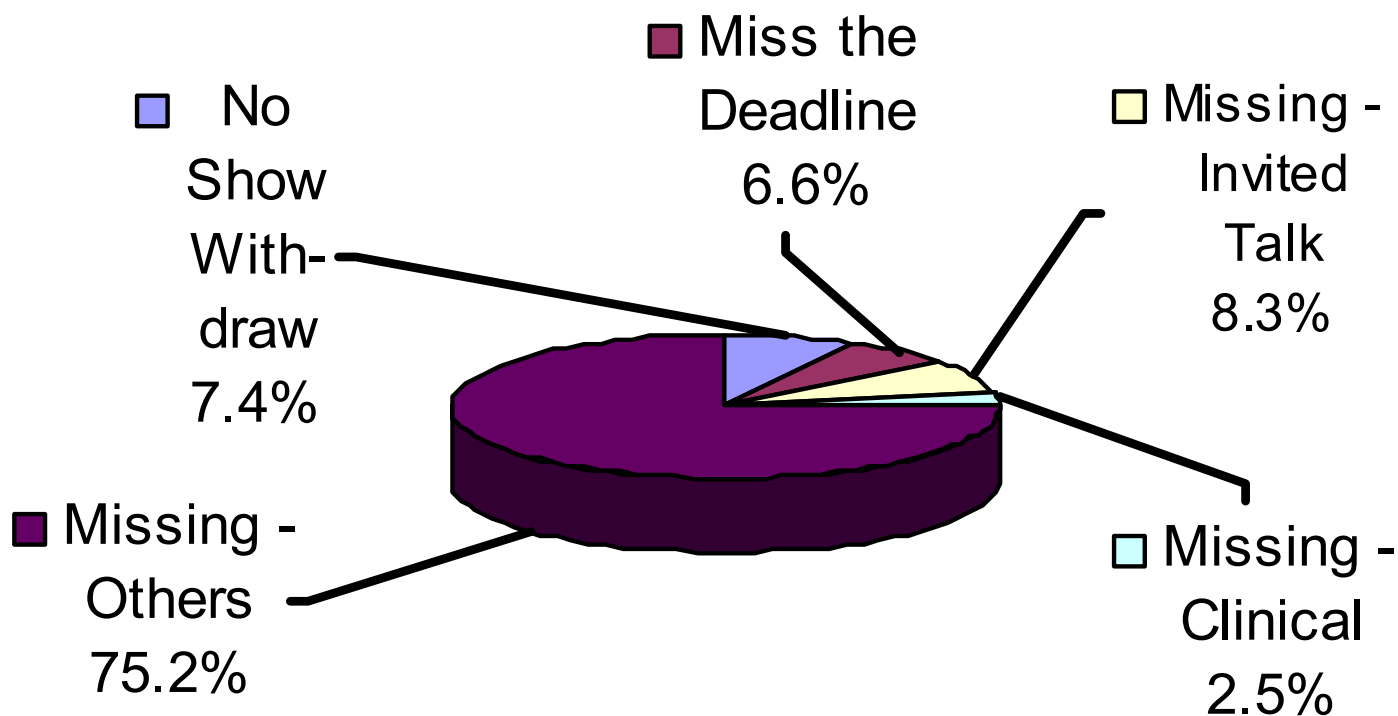


7. Presentations of accepted abstracts (674) in the conference



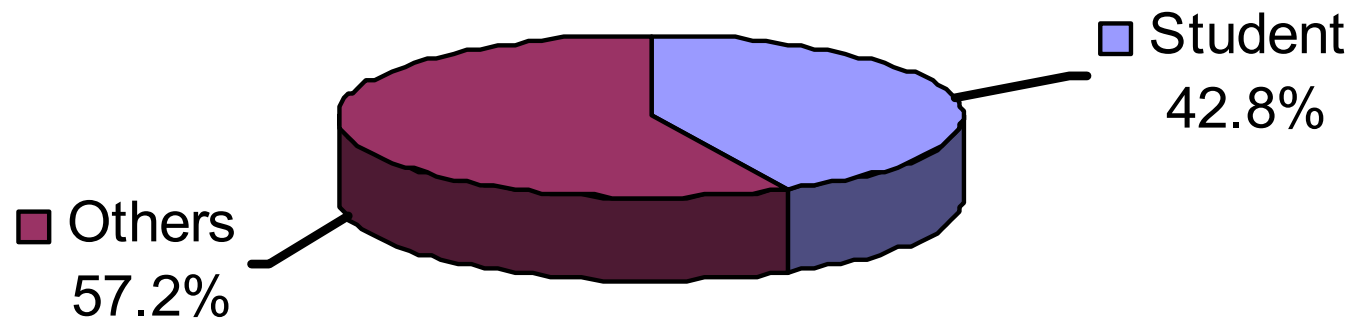
8. Categories of papers that are not published (121)

Papers Not in Proceedings (Total 121 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)

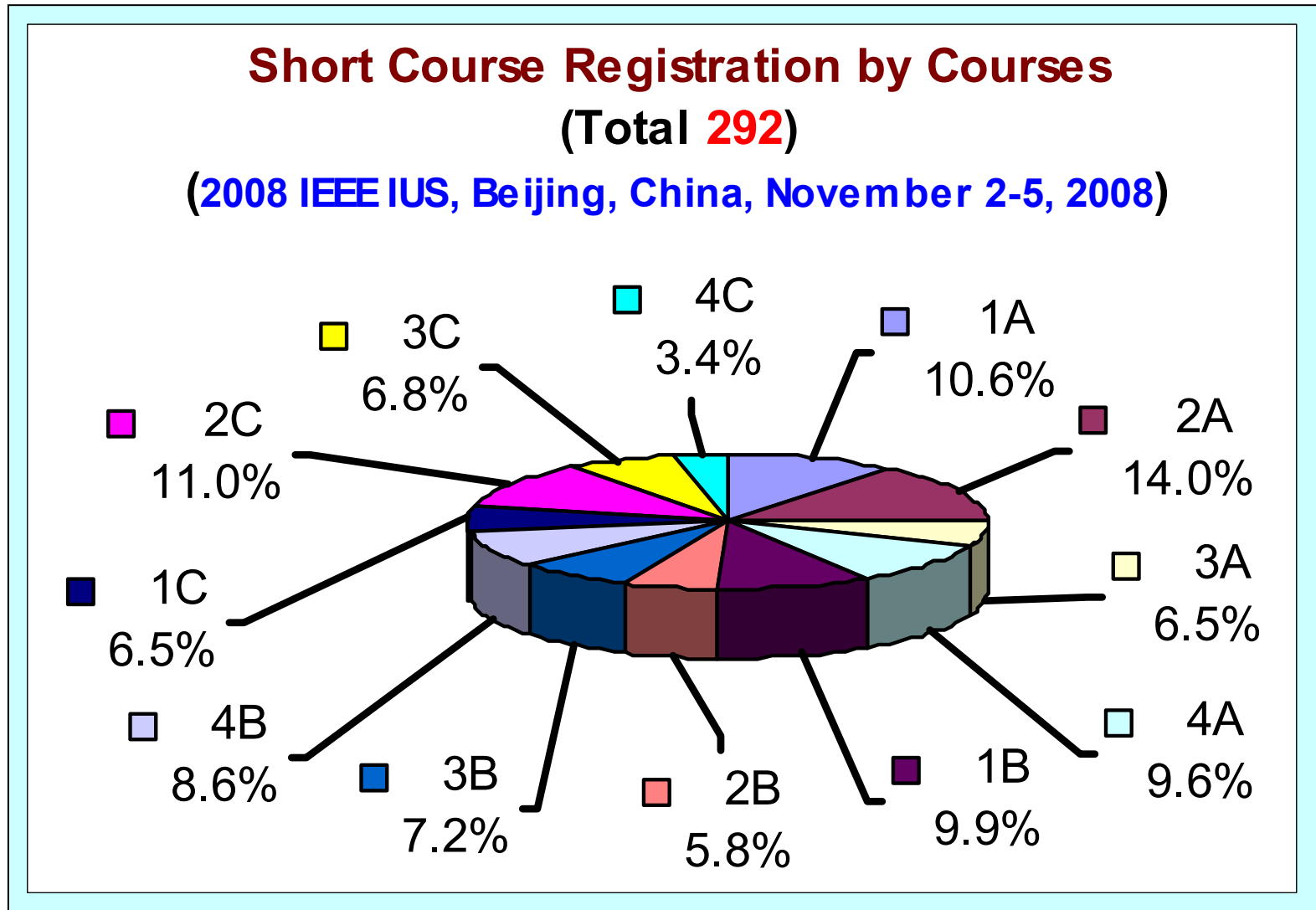


9. Short course registration (292) types

Short Course Registration Types (Total 292) (2008 IEEE IUS, Beijing, China, November 2-5, 2008)



10. Attendances (total 292) of each of the 12 short courses



A list of the 12 short courses

- **8:00 A.M. - 12:00 Noon, Sunday, November 2, 2008:**
 - Short Course 1A** (Conference Room 311A/B): **Medical Ultrasound Transducers**, *Douglas G. Wildes* and *L. Scott Smith*, GE Global Research Center, Niskayuna, NY, USA.
 - Short Course 2A** (Conference Room 307): **Ultrasound Imaging Systems: from Principles to Implementation**, *Kai E. Thomenius*, GE Global Research Center, Niskayuna, NY, USA.
 - Short Course 3A** (Conference Room 308): **Photoacoustic Imaging and Sensing**, *Stanislav Emelianov*, Biomedical Engineering Department, University of Texas at Austin, USA.
 - Short Course 4A** (Conference Room 311C): **Estimation and Imaging of Tissue Motion and Blood Velocity**, *Hans Torp* and *Lasse Lovstakken*, Department of circulation and medical imaging, Norwegian University of Science and Technology, Trondheim, Norway.
- **1:00 P.M. - 5:00 P.M, Sunday, November 2, 2008:**
 - Short Course 1B** (Conference Room 311A/B): **Ultrasound Elastography: Quantitative Approaches**, **Jeffrey Bamber* and ***Paul Barbone*, **Institute of Cancer Research and Royal Marsden Hospital, UK. **Boston University, USA.*
 - Short Course 2B** (Conference Room 307): **Acoustic Microscopy - Fundamentals and Applications**, **Roman Gr. Maev*, ***Naohiro Hozumi*, ****Kazuto Kobayashi*, and *****Yoshifumi Saijo*, **Centre for Imaging Research and Advanced Materials Characterization, University of Windsor, Ontario, Canada. **Department of Electrical & Electronic Engineering, Aichi Institute of Technology, Toyota, Japan. ***Honda Electronics Co. Ltd., Aichi, Japan. ****Tohoku University, Sendai, Japan.*
 - Short Course 3B** (Conference Room 308): **Therapeutic Ultrasound**, *Lawrence A. Crum*, Applied Physics Laboratory, University of Washington, Seattle, WA, USA.
 - Short Course 4B** (Conference Room 311C): **SAW Modeling Techniques**, *Victor P. Plessky*, GVR Trade SA, Bevaix, Switzerland.
- **6:00 P.M. - 10:00 P.M, Sunday, November 2, 2008:**
 - Short Course 1C** (Conference Room 311A/B): **Ultrasound Contrast Agents: Theory and Experiment**, **Nico de Jong* and ***Michel Versluis*, **Erasmus MC, The Netherlands. **University of Twente, The Netherlands.*
 - Short Course 2C** (Conference Room 307): **CMUTs: Theory, Technology, and Applications**, *B.T. Khuri-Yakub*, *Ömer Oralkan*, and *Mario Kupnik*, E.L. Ginzton Laboratory, Stanford University, USA.
 - Short Course 3C** (Conference Room 308): **Time Reversal Acoustics**, *Mathias Fink*, École Supérieure de Physique et de Chimie de la Ville de Paris, France.
 - Short Course 4C** (Conference Room 311C): **Acoustical Near-Field Imaging**, *Walter Arnold*, Fraunhofer Institute for Non-Destructive Testing, Saarbrücken, Germany.